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Title: AC TESTING OF LEAKAGE CURRENT IN INTEGRATED CIRCUITS USING RC TIME CONSTANT (As Amended)

## IN THE ABSTRACT OF THE DISCLOSURE

Please amend the Abstract as follows:

## **Abstract of the Disclosure**

A method of leakage test for testing an integrated circuit includes applying a voltage to one of the pins of the integrated circuit. The pin is floated for a predetermined time. A measurement is performed after the predetermined time. The measurement involves by sampling the RC time constant of leakage current of the pins of the integrated circuit.